Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/055,560	LIN ET AL.	
Examiner	Art Unit	
James M. Mitchell	2813	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Zast Csee printed	6/30/06	GUN	
257/666, 635,636 758,759,760 (see printant)			
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